

## ABSTRACT OF THE DISCLOSURE

An arrangement for the identification of a substrate (S) having at least one identification marking (I), comprising

a turntable (2) for rotating a substrate (S) placed thereon;

an illumination source (4) and a receiving device (5) for evaluating the intensity of the light emerging from the illumination source (4), the edge zone of the substrate (S) placed on the turntable (2), upon rotation thereof, influencing the light intensity striking the receiving device (5);

a device (6) for reading the identification marking (I), having a sensing region (E); and

a calculation device that calculates a manipulated variable for a correction rotation angle about the rotation axis (A) for alignment of the identification marking (I) with respect to the sensing region (E), and a manipulated variable for a correction motion for changing the position of the sensing region (E) with respect to the rotation axis (A) or with respect to the actual position of the identification marking (I), and outputs them to a positioning device.

A corresponding identification method is also described.

(FIG. 1)

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